

# SEMICONDUCTOR DEVICES II: Part I - Information Processing with MEMS

## Lecture #7

Adrian M. Ionescu, EPFL, Switzerland

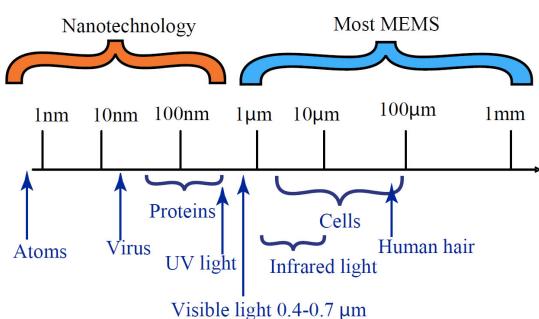
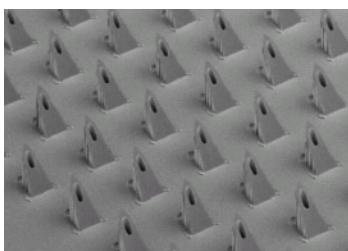
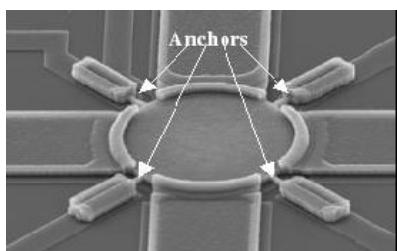
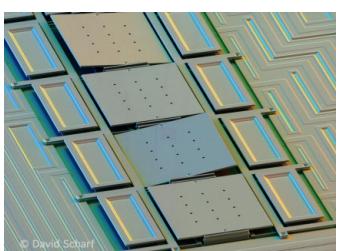
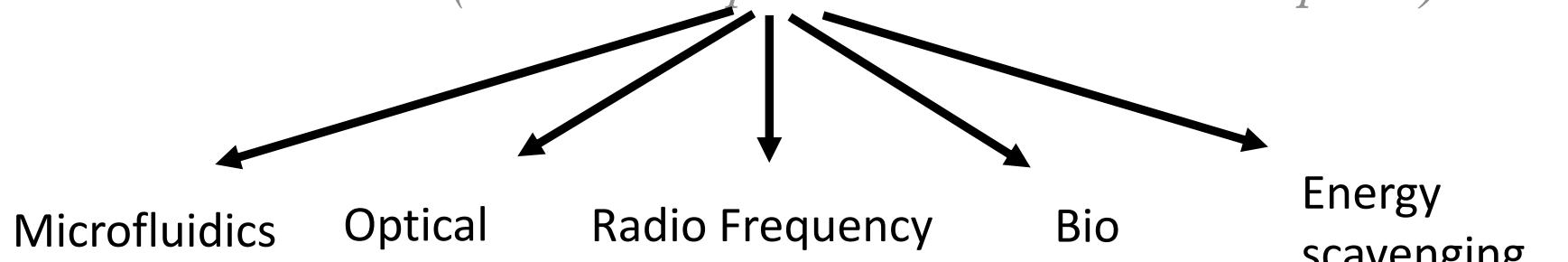
Andras Kis, EPFL, Switzerland

# Outline

- **Introduction: Micro/Nano-Electro-Mechanical Systems**
- **M/NEM switches/relays for logic**
- **M/NEM resonators:**
  - Passive resonators, filters and mixers
  - Resonant gate or body transistors to amplify small signals
- **M/NEM inertial sensors:**
  - Accelerometers

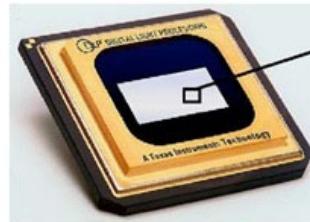
# Introduction

MEMS = Micro-Electro-Mechanical Systems  
*(include suspended and/or movable parts)*

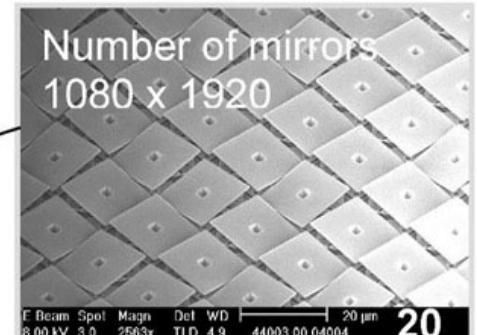


# Information processing with MEMS short history

- 1967 - Invention of **surface micromachining** (Nathanson, Resonant Gate Transistor)
- 1970 - Micromachined **silicon pressure sensor** demonstrated (Petersen)
- 1970 - First **silicon accelerometer** demonstrated (Kulite)
- 1977 - First **capacitive pressure sensor** (Stanford)
- 1984 - First **polysilicon MEMS device** (Howe, Muller)
- 1988 - Rotary **electrostatic side drive motors** (Fan, Tai, Muller)
- 1989 - Lateral **comb drive** (Tang, Nguyen, Howe)
- 1991 - Polysilicon hinges developed (Pister, Judy, Burgett, Fearing)
- 1992 - **Multi User MEMS Process** (MUMPs) is introduced by MCNC, (now MEMSCAP)
- 1993 - First **surface micromachined accelerometer** (ADXL50) sold, (Analog Devices)
- 1998 - Demonstration of **DMD (Digital Mirror Device)**, (Texas Instruments)



(a)

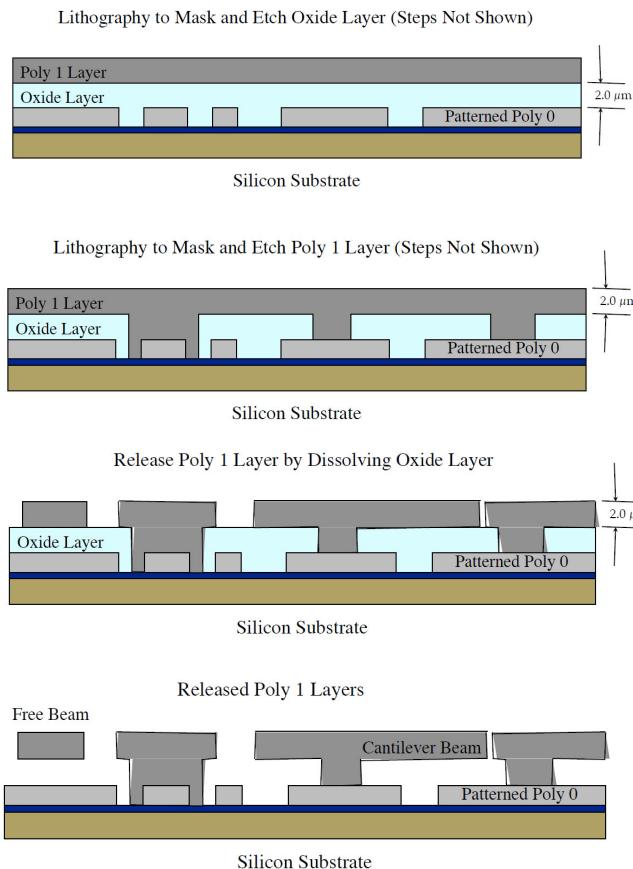
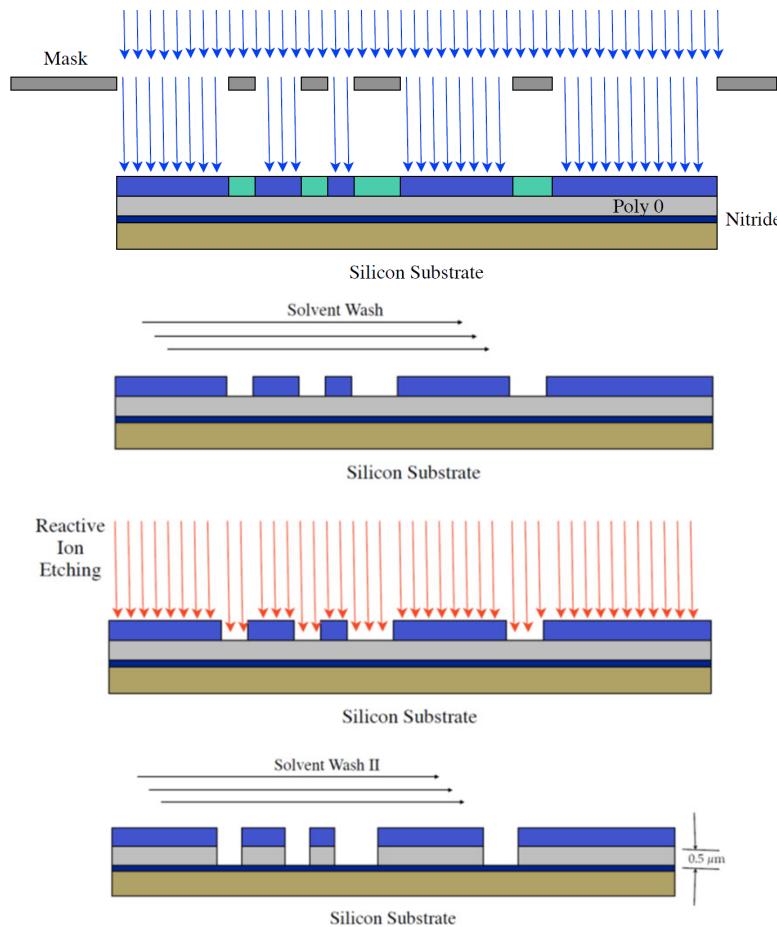


(b)

# MEMS micro/nano fabrication

- MEMS are fabricated with a unique set of technologies collectively referred to as 'microfabrication' or 'micromachining'
- There are two main areas of micromachining:
  - **Surface Micromachining**, which is based on the successive deposition and etching of thin films of material such as silicon nitride, polysilicon, silicon oxide and gold.
  - **Bulk Micromachining**, which is based on the etching and bonding of thick sheets of material such as silicon oxides and crystalline silicon.

# Example of surface micromachining microcantilever fabrication



# MEMS actuation mechanisms

	Voltage (V)	Current (mA)	Power (mW)	Size	Switch time (μs)	Force (contact) (μN)
Electrostatic	1-100	~0	~0	Small	1-200	50-1000
Thermal	3-5	1-100	<500	Large	300-10'000	500-5'000
Magnetic	3-5	10-100	<500	Medium	300-1'000	50-200
Piezoelectric*	3-20	~0	~0	Medium	50-500	50-200

\* Recent attention to quartz, GaAs, ZnO, PZT:  $\text{Pb}(\text{Zr}_x\text{Ti}_{1-x})\text{O}_3$ :

mechanical stress polarizes the material → electrical field, works also reversely!

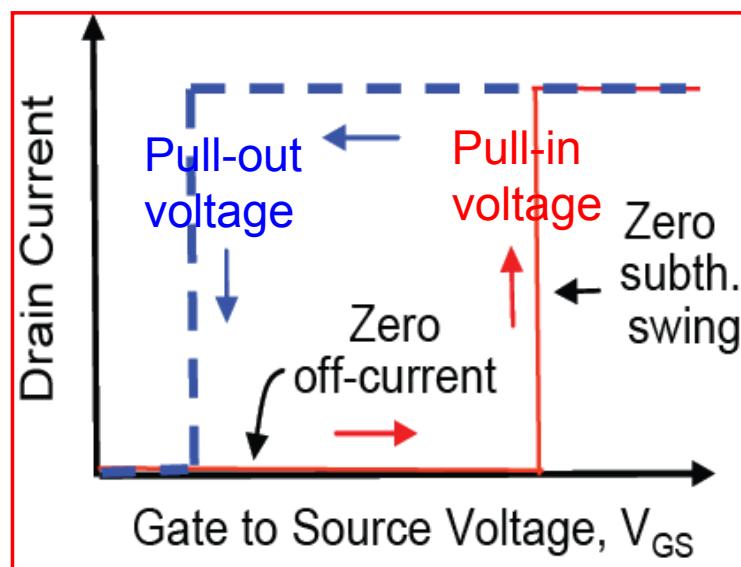
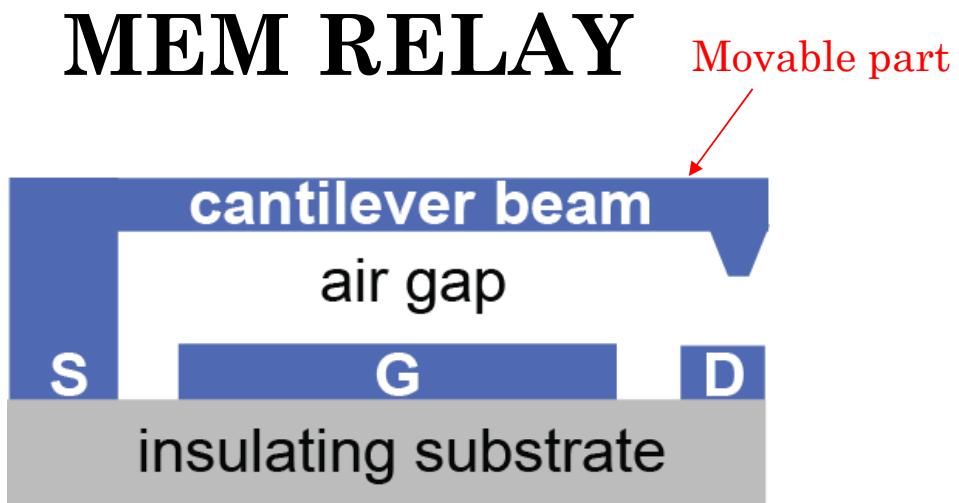
Table adapted after Rebeiz [1]

[1] Gabriel M. Rebeiz, RF MEMS: Theory, Design, and Technology.  
ISBN: 978-0-471-20169-4, Wiley, March 2003.

# MEMS Switch/Relay

Electro-mechanical information processing:

as a **multi-state logic**, with the logic states dictated by a spatial configuration of movable objects



# Electromechanical design of pull-in voltage

Pull-in / Pull-out electromechanical hysteresis of capacitive switch

$g_o$  = zero - voltage gap spacing

$$g = g_o - x$$

$$g_{\text{eff}} = g_o + \frac{g_{\varepsilon}}{\varepsilon_r} \approx g_o$$

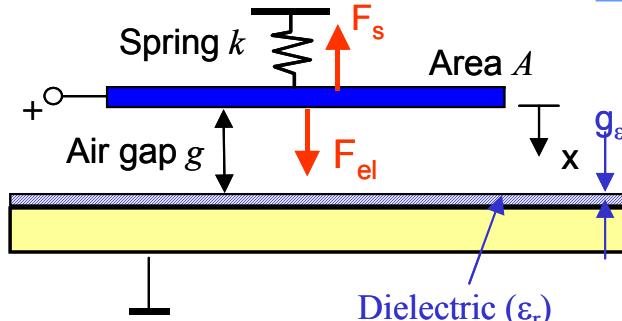
$$F_{\text{el}} = \frac{\varepsilon_0 A V^2}{2g^2}$$

$$F_s = k(g_o - g)$$

$$C_{\text{up}} = C(V = 0) = \varepsilon_0 \frac{A}{g_{\text{eff}}}$$

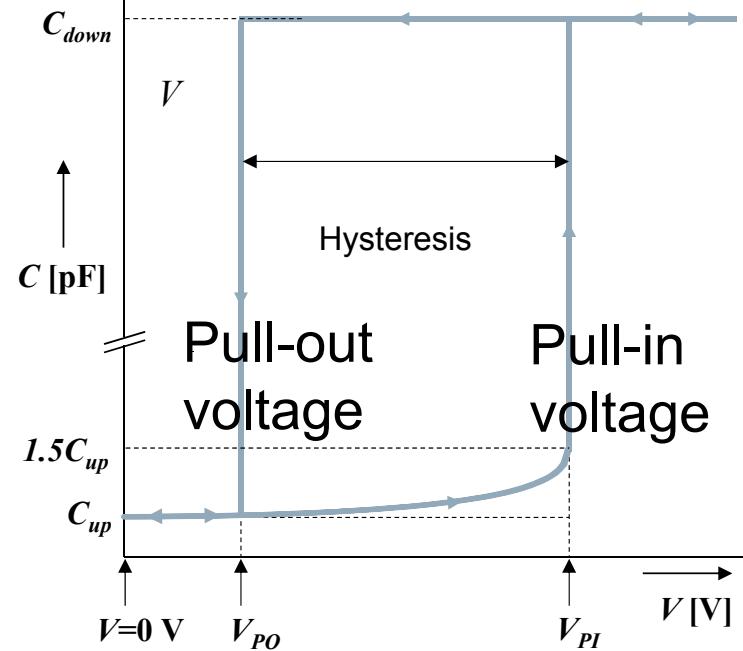
$$C_{\text{down}} = C(V > V_{\text{PI}}) = \varepsilon_0 \varepsilon_r \frac{A}{g_{\varepsilon}}$$

$$\frac{C_{\text{down}}}{C_{\text{up}}} = \frac{\varepsilon_r g_{\text{eff}}}{g_{\varepsilon}} \approx \frac{\varepsilon_r g_o}{g_{\varepsilon}}$$



$$V_{\text{PO}} = \sqrt{\frac{2kg_o g_{\varepsilon}^2}{\varepsilon_r^2 \varepsilon_0 A}}$$

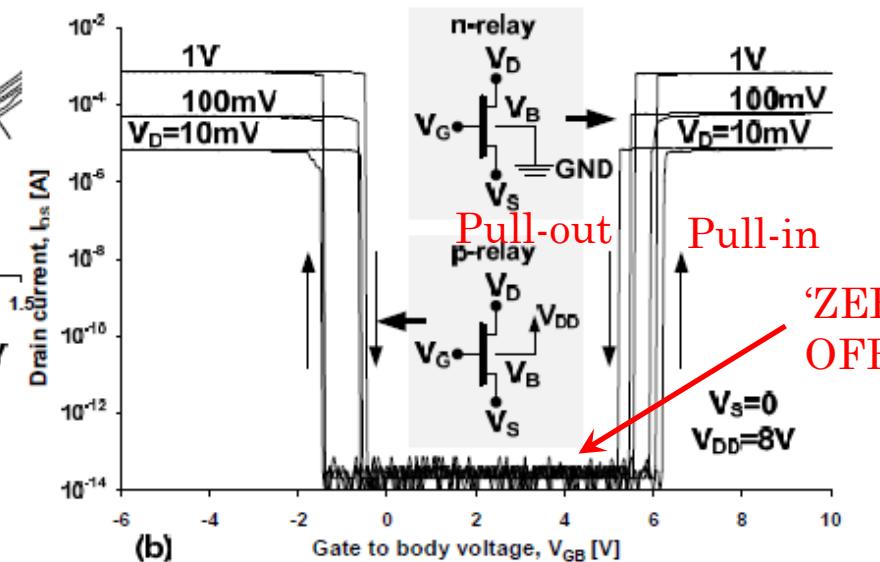
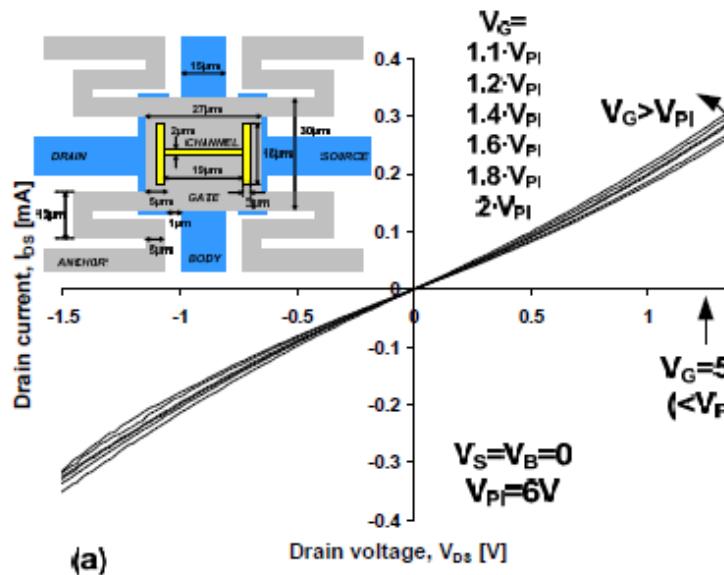
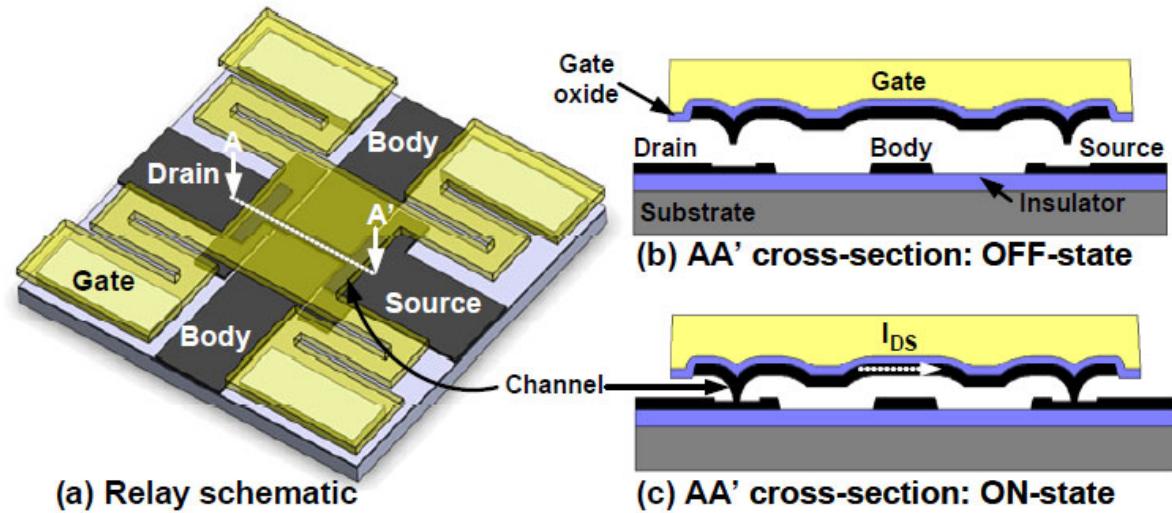
$$V_{\text{PI}} = \sqrt{\frac{8}{27} \frac{k g_{\text{eff}}^3}{\varepsilon_0 A}}$$



Pull-in @ 1/3 of the air gap!

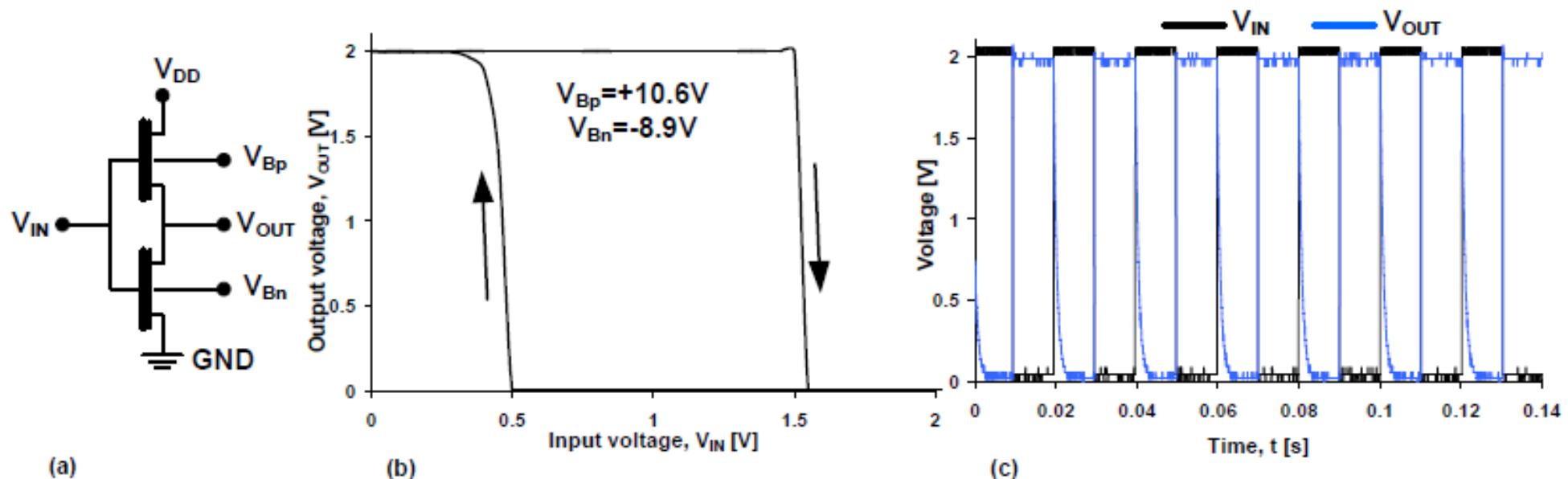
Source: H. Tilmans, IMEC.

# UC Berkeley's 4-terminal relay



# ... and mechanical inverter operation

Hysteretic voltage transfer characteristic

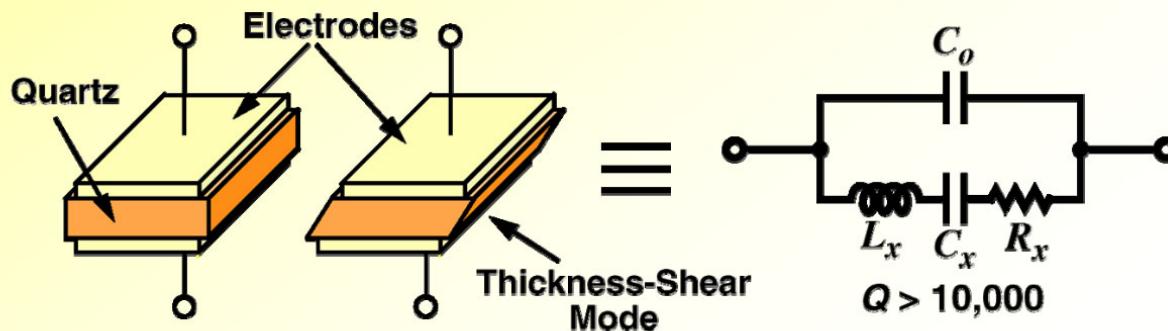


**Fig. 6.18.** (a) Relay inverter schematic. Two similar devices are operated in n-type and p-type modes. (b) Measured static and (c) dynamic characteristics [34].  $V_{IN}$  is a  $f=50$ Hz square wave.

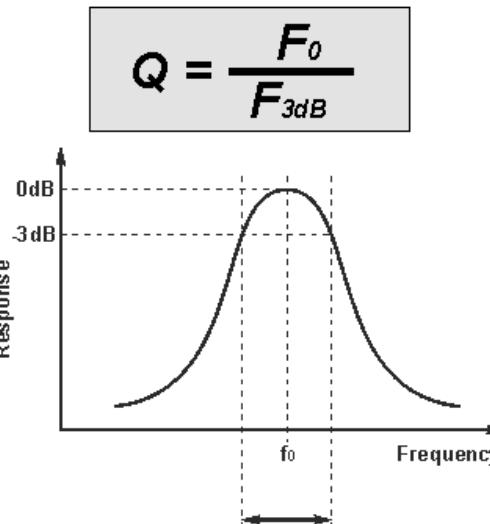
# Rationale for MEMS resonators: High Quality factor, Q

Information processing as **vibrational modes** of mechanical elements, based upon waves.

- **Problem:** IC's cannot achieve Q's in the thousands
  - ↳ transistors → consume too much power to get Q
  - ↳ on-chip spiral inductors → Q's no higher than ~10
  - ↳ off-chip inductors → Q's in the range of 100's
- **Observation:** vibrating mechanical resonances →  $Q > 1,000$
- **Example:** quartz crystal resonators (e.g., in wristwatches)
  - ↳ extremely high Q's ~ 10,000 or higher ( $Q \sim 10^6$  possible)
  - ↳ mechanically vibrates at a distinct frequency in a thickness-shear mode



C. T.-C. Nguyen, FCS'05 Tutorial: "MEMS for Frequency and Timing References", 8/28/05



Q of a tuned circuit with respect to its bandwidth

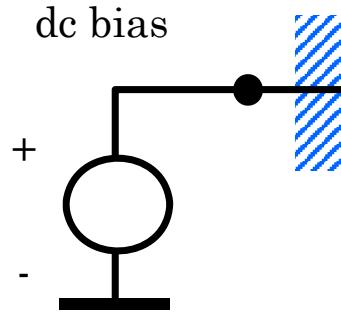
$$Q = \frac{E_{\text{stored}}}{E_{\text{lost per cycle}}}$$

# Principle

## Micro-Electro-Mechanical resonator

Resonance frequency:

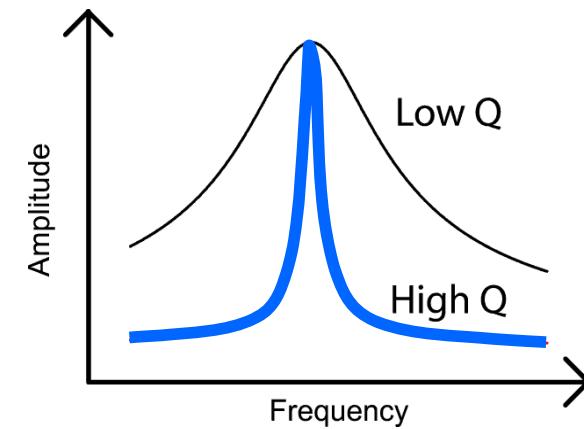
$$f_{res} = \frac{1}{2\pi} \sqrt{\frac{k_{eff}}{m_{eff}}}$$



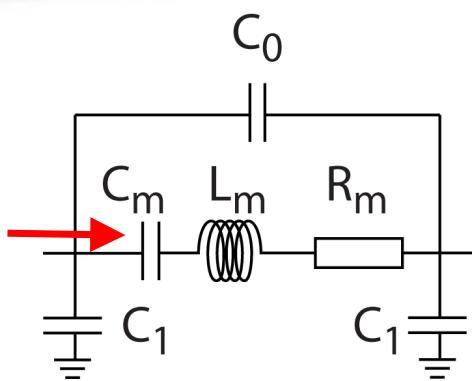
Input:  
ac signal

Clamped-clamped beam

Output signal:



# MEM resonator is tuneable in frequency



$$Lq'' + Rq' + (1/C)q = V_i$$

L: motional inductance    R: Motional resistance     $1/C$ : Stiffness

*Mechanical domain equations:*

$$mx'' + bx' + kx = F$$

*Electrical domain analogy:*

Tuning the resonance frequency: stiffness!

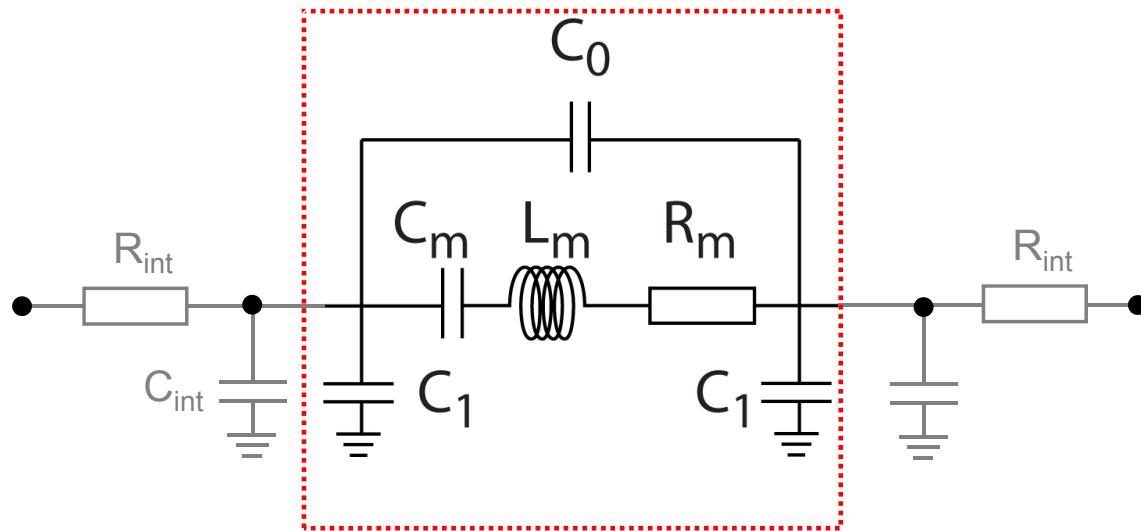


# Motional to electrical equivalent parts and electrical small signal circuit

$$L_m = \frac{m_{eff}}{2V_{DC}^2 \left( \frac{\partial C}{\partial x} \right)^2}$$

$$C_m = \frac{2V_{DC}^2 \left( \frac{\partial C}{\partial x} \right)^2}{k_{eff}}$$

$$R_m = \frac{\omega m_{eff}}{2QV_{DC}^2 \left( \frac{\partial C}{\partial x} \right)^2}$$



Motional resistance



$$R_m = \frac{k_{eff} g^4}{\epsilon_o^2 A^2 \omega Q V_{DC}^2}$$

# Need for low motional resistance & nanogaps

Motional resistance:

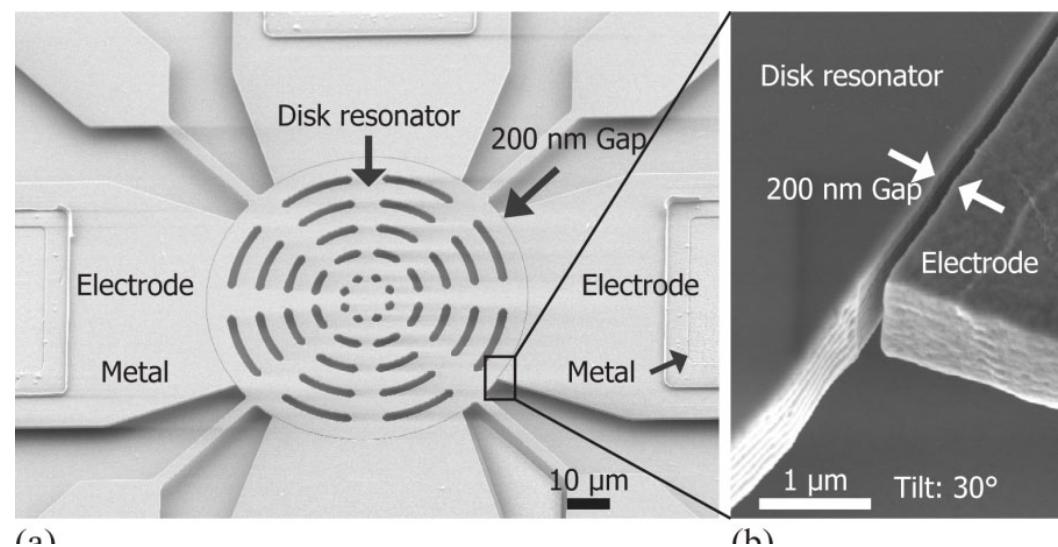
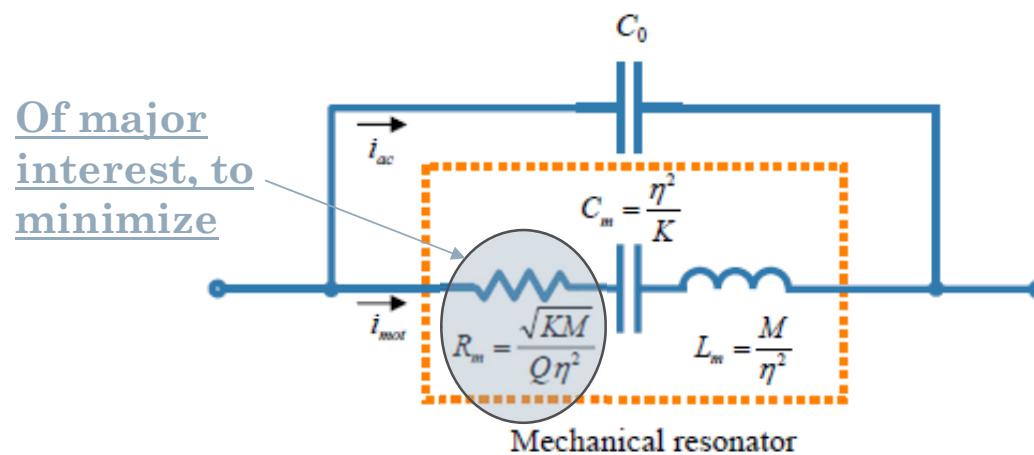
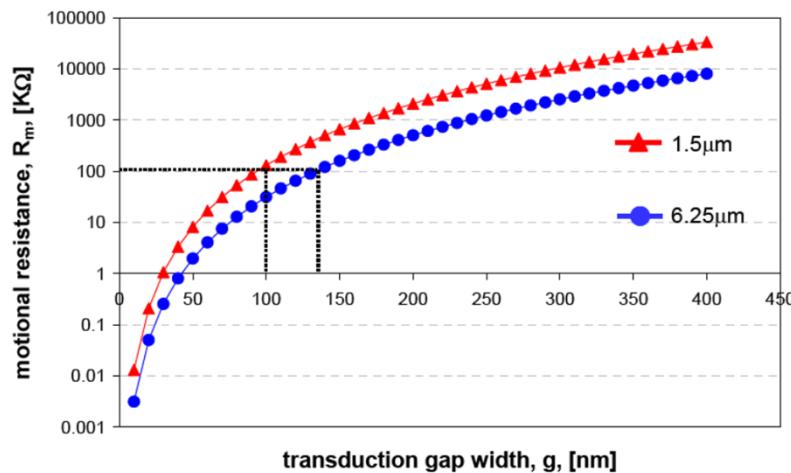
$$R_m \sim \text{gap}^4/\text{voltage}^2$$

(1/10 gap, 1/10'000  $R_m$ )

Example:

$f_{\text{res}} = 31\text{MHz}$ ,  $r = 40\text{um}$ ,  $t_{\text{Si}} = 1.25\text{um}$

**Deep submicron gaps: 100-200nm,**  
 $Q > 20'000$ ,  $R_m = 130\text{kOhm}$



# Quality factor mechanisms

$$Q \equiv \omega * \frac{\overline{Energy stored}}{Energy loss / sec} \equiv \frac{\omega_o}{\Delta\omega}$$

Mechanism #1:  
Material defect losses

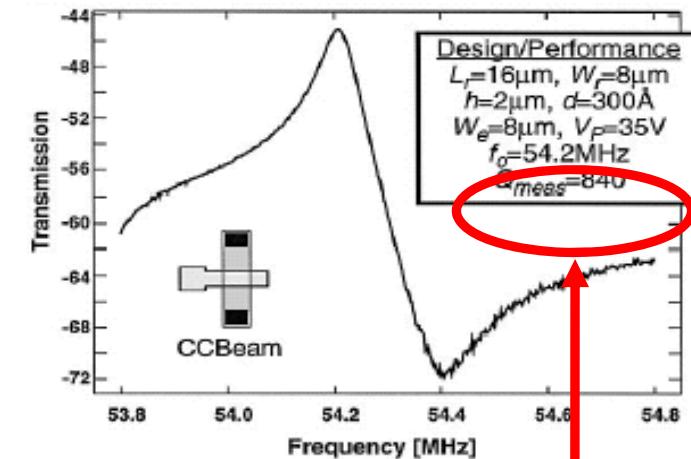
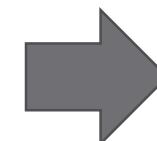
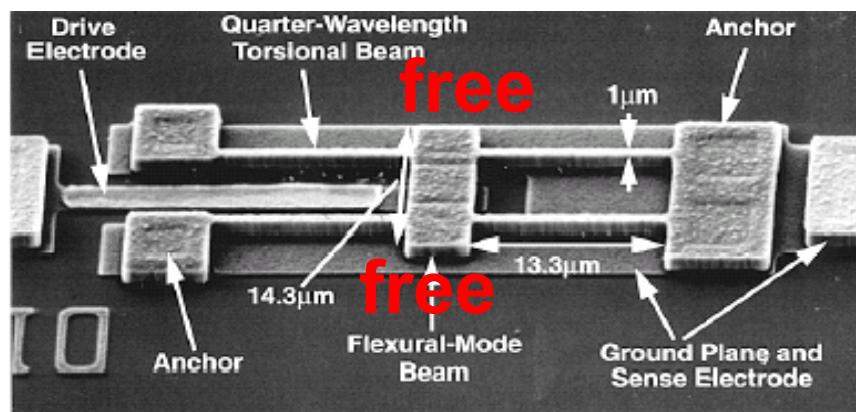
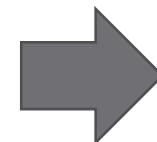
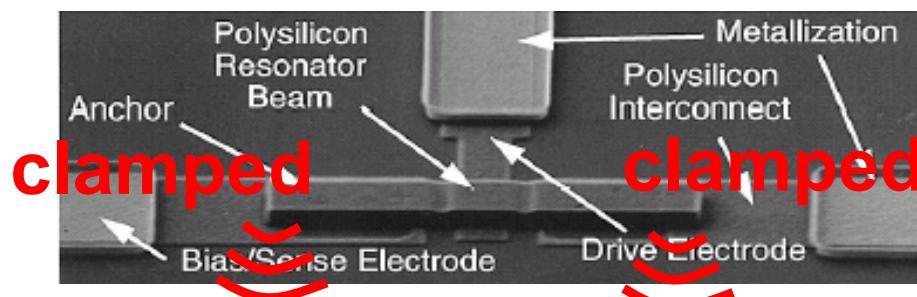
Mechanism #3: Gas damping  
(not an issue in vacuum or  
for bulk resonators)

$$\frac{1}{Q} = \frac{1}{Q_{defects}} + \frac{1}{Q_{TED}} + \frac{1}{Q_{viscous}} + \frac{1}{Q_{sup\ port}}$$

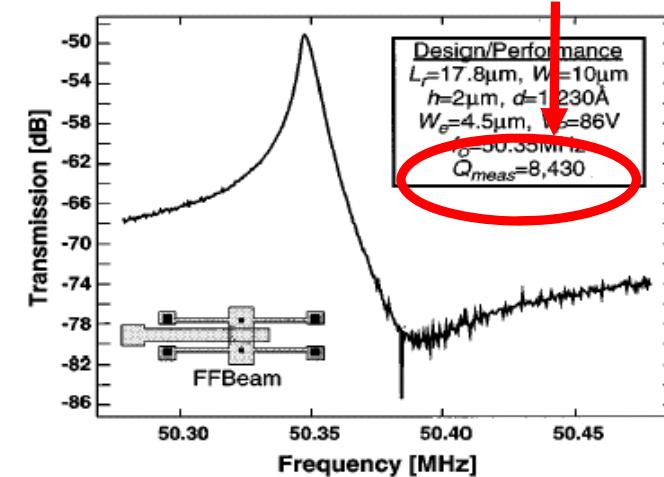
Mechanism #2: Thermoelastic  
damping (TED)

Mechanism #4: Anchor losses, needs  
design optimization, important @  
high frequency

# Quality factor: impact of anchor loss



Effect of energy anchor loss



K. Wang, A.C. Wong, C.T. Nguyen, JMEMS, Vol. 9, Sept. 2000.

# MEMS filters

**Resonator beam:** has two electrical inputs  $v_e$  ( $=v_i$ ) and  $v_b$  ( $=V_P$ )

$$F_d = \frac{\partial E}{\partial x} = \frac{1}{2} (v_e - v_b)^2 \frac{\partial C}{\partial x} = \frac{1}{2} (v_e^2 - 2v_e v_b + v_b^2) \frac{\partial C}{\partial x}$$

$x$  = beam displacement and

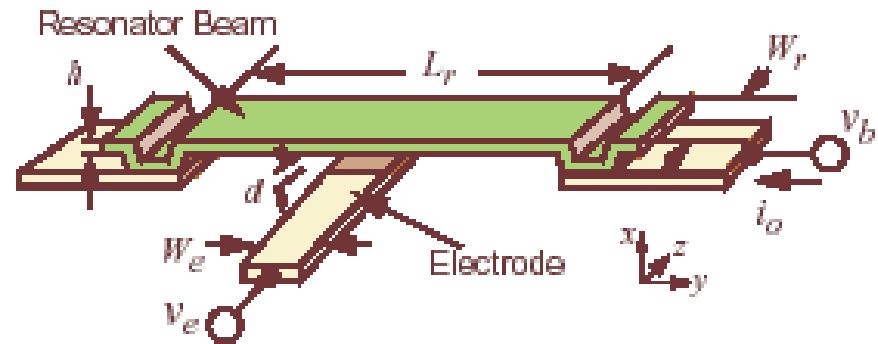
$$\frac{\partial C}{\partial x} = -\frac{\epsilon W_r W_e}{d_0^2}$$

→ filtering applications

$$v_b = V_P \text{ (dc bias)}, \quad v_e = v_i = V_i \cos \omega_i t$$

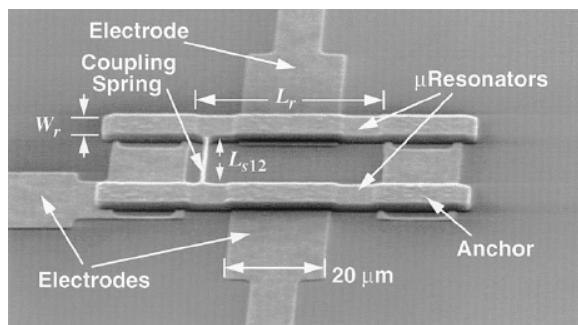
$$F_d = \frac{\partial C}{\partial x} \left( \frac{V_P^2}{2} + \frac{V_i^2}{4} \right) - V_P \frac{\partial C}{\partial x} V_i \cos \omega_i t + \frac{\partial C}{\partial x} \frac{V_i}{4} \cos 2\omega_i t$$

Off resonance dc force      Component used in filtering

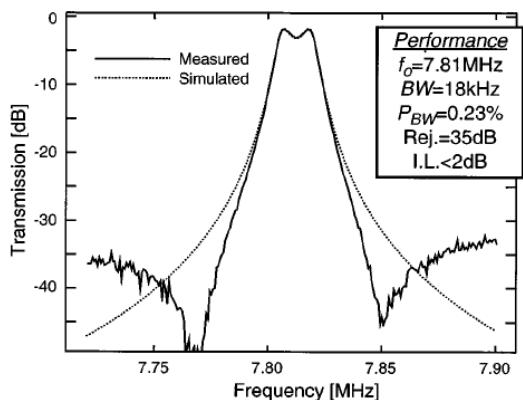


# MEMS filters: examples

## 2-beam MEM filter

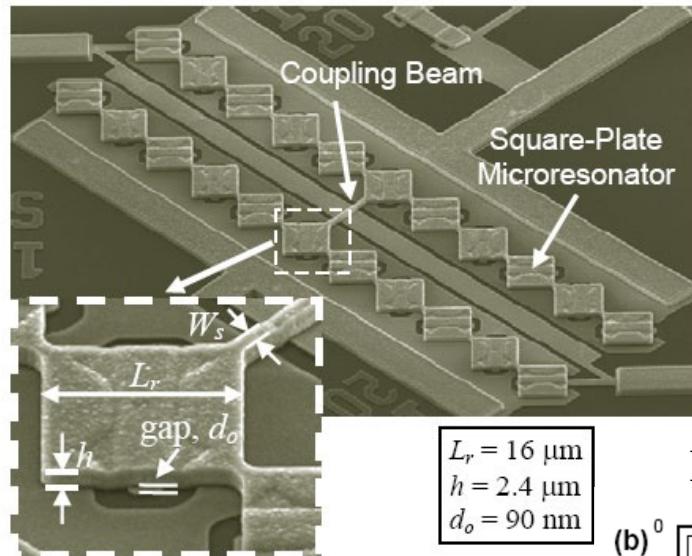


Band-pass filter



C.T.Nguyen, chapter in 'RF Technologies for Low Power Wireless Communications', Wiley, 2002.

## Many coupled devices



Band-pass filter

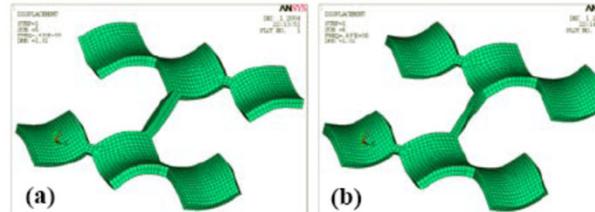
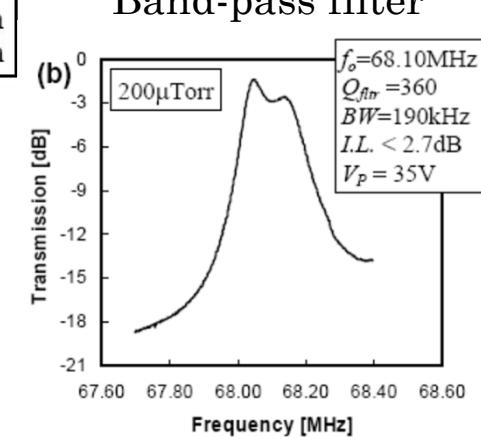
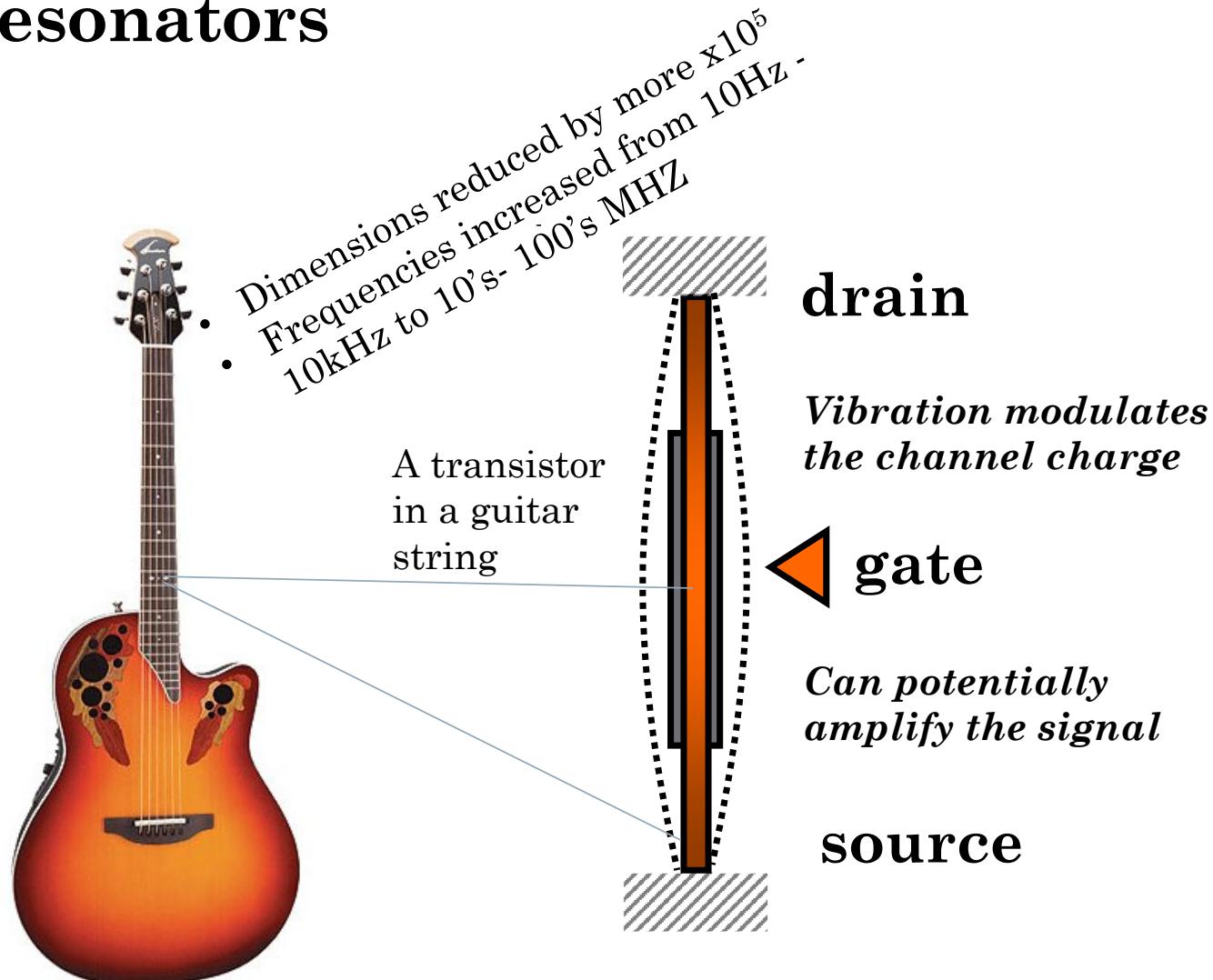


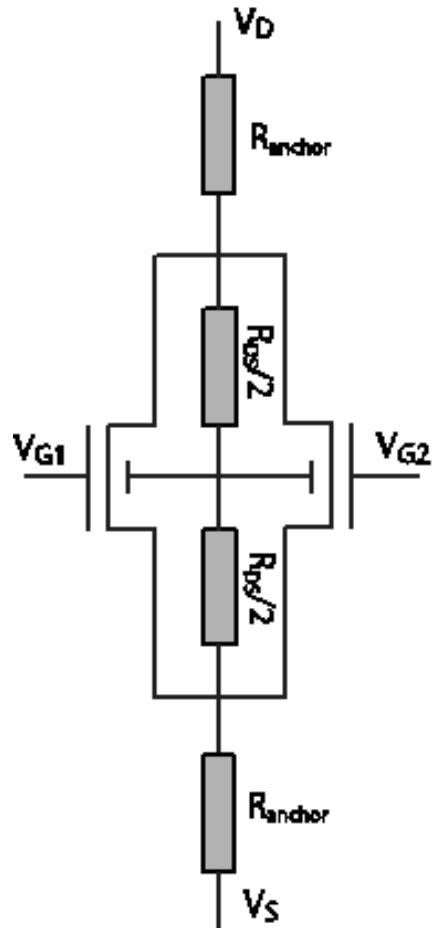
Fig. 3: ANSYS-simulated (a) in-phase and (b) out-of-phase mode shapes of the coupled-array filter of Fig. 2.



# Resonant gate or body transistors: active MEMS resonators

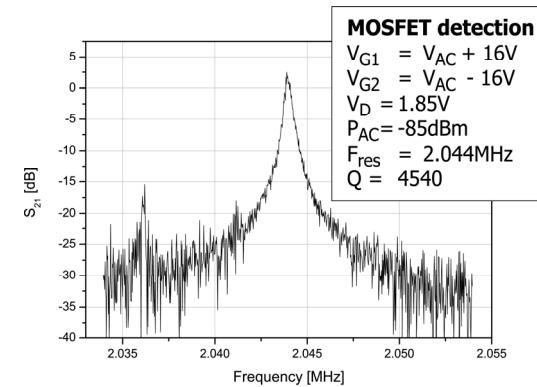


# Vibrating body FET



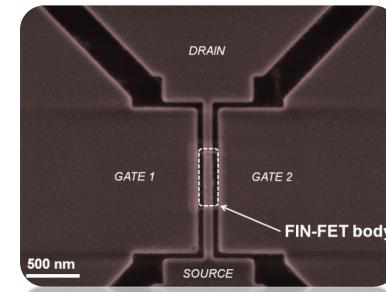
D. Grogg et al, IEDM 2008.

frez = 2MHz



$R_m = -30\Omega$ , amplifies!

Fully-depleted RB-FET:

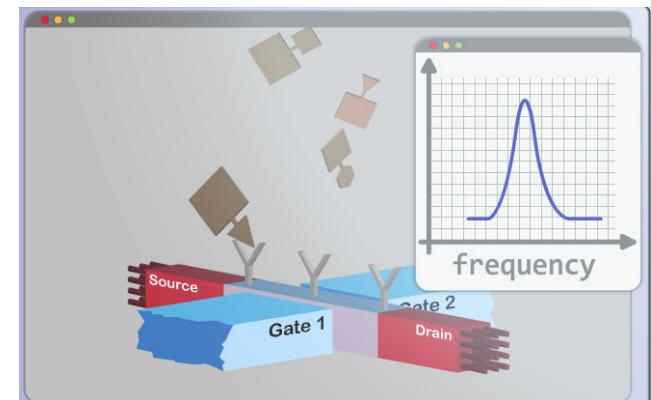


frez = 70MHz

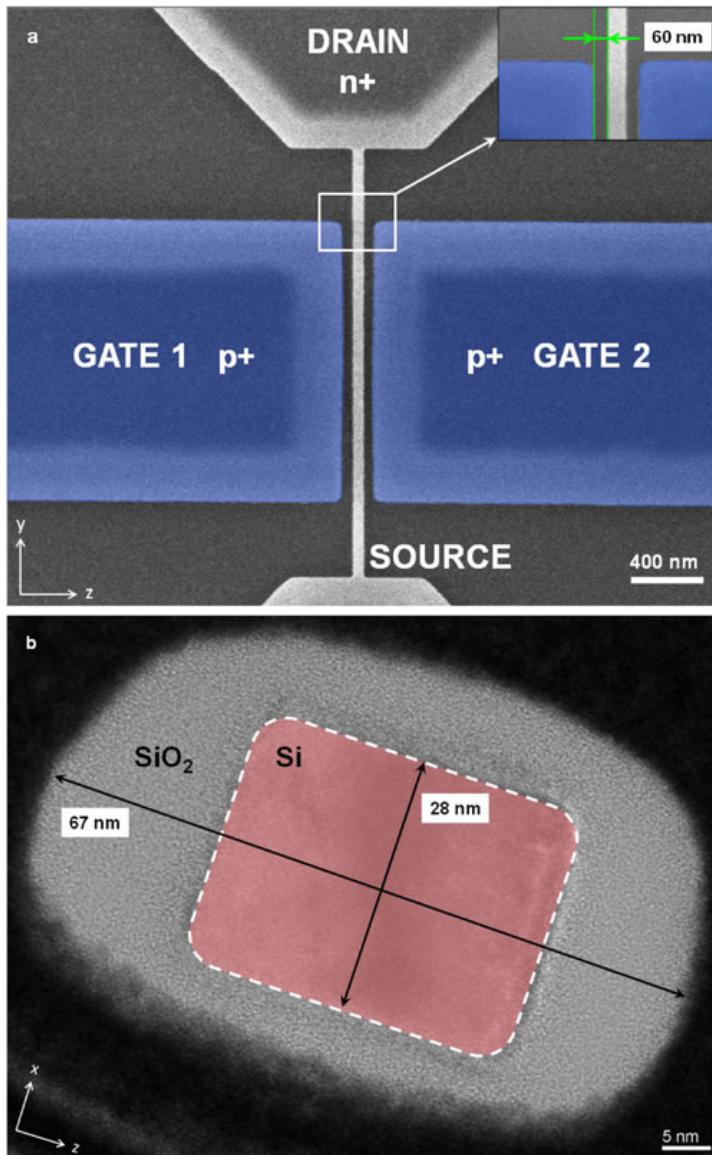
# NEMS nanobalances for molecule/atom sensing

Ultra-scaled resonant transistor:  
f<sub>res</sub> ~70 – 200MHz

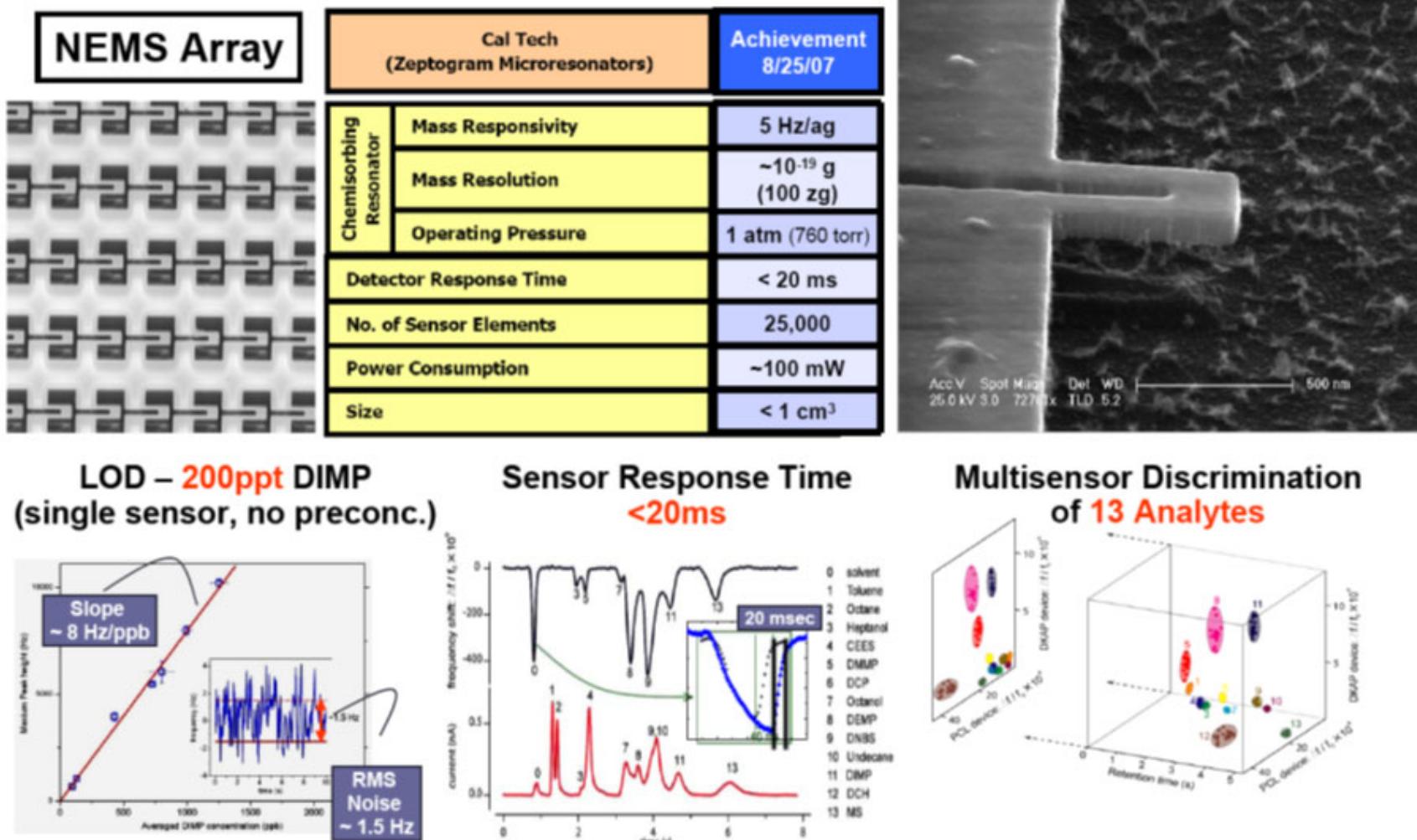
$$f_{res} = \frac{1}{2\pi} \sqrt{\frac{k_{eff}}{m_{eff}}}$$



- Mass accretion of 1.3 ag (top) detected: corresponds to approx. 4000 gold atoms
- Scalable to detect ~10 atoms
- **Applications:**
  - ✓ biomarkers for early cancer detection
  - ✓ integrated gas sensors
  - ✓ integrated particle sensors



# Gas sensors with NEMS (by Caltech)



# Conclusions: M/NEM resonators

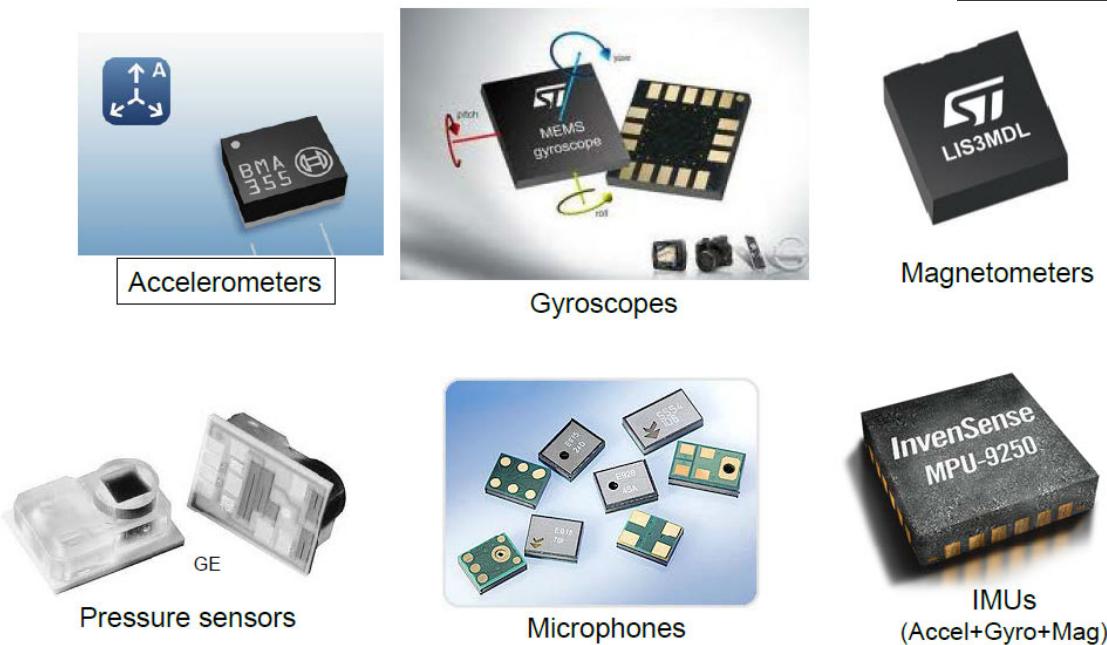
- Large opportunities for **N/MEM resonators in enabling new low power analog/RF systems** (co-integration with silicon ICs) for filtering and mixing
- Future role of vibrant (resonant) FET devices for low power **integrated sensing**
- **NEM resonators**: key components for future advanced signal electro-mechanical processing, from analog/RF to sub-attogram sensing.

# Micro-Electro-Mechanical Systems (MEMS) Motion Sensors

## Growing Market for MEMS Motion Sensors

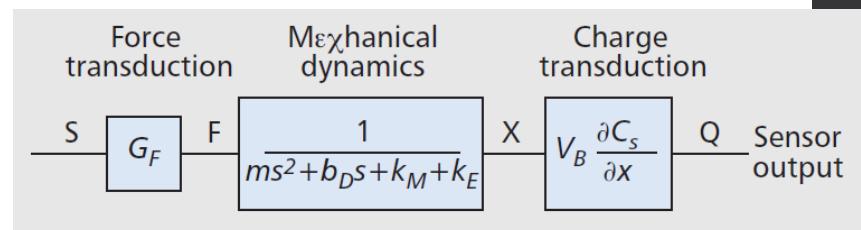
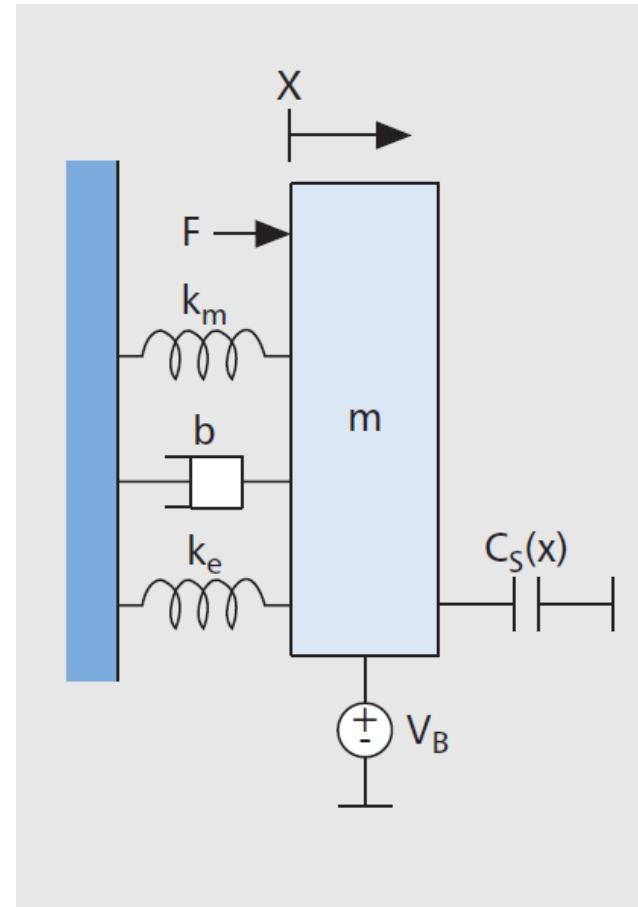


## MEMS sensors in navigation systems



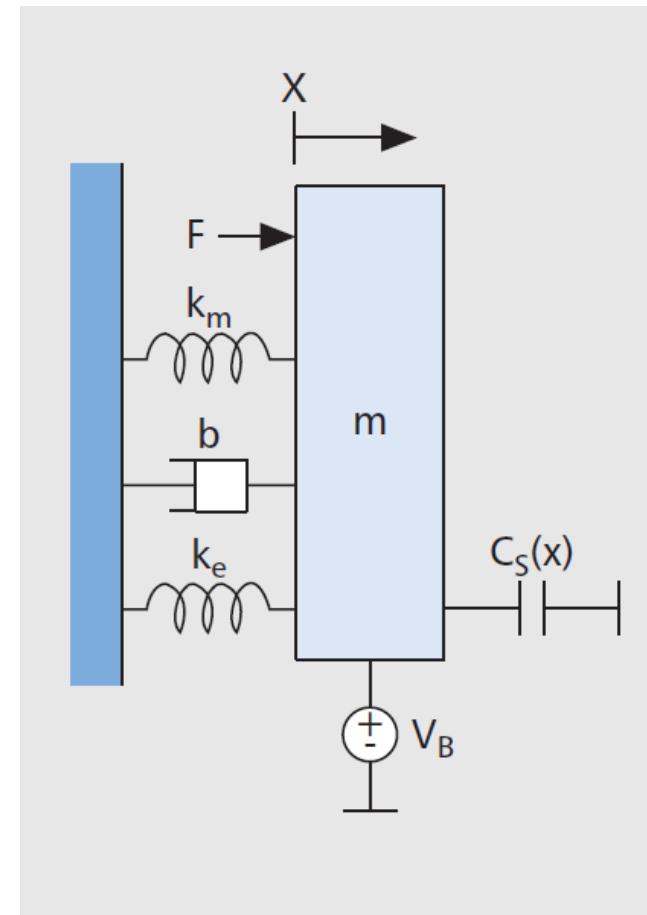
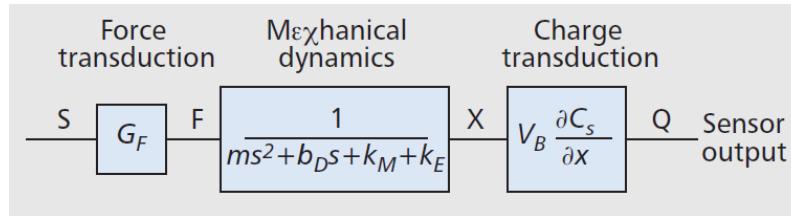
# MEMS Inertial Sensors

- In any inertial system, a proof mass,  $m$ , is suspended on a mechanical frame by a spring,  $k_m$ , and responds to an input force,  $F$ , mirroring the quantity to be measured.
- The input force causes a displacement,  $x$ , of the mass, and the displacement is measured to sense the force coming from:
  - **acceleration of the mass**, as is the case in an **accelerometers**
  - from a **Coriolis acceleration**, resulting from angular rotation of the mass, as is the case in a **vibratory rate gyroscope**.
- Design optimization of inertial sensors aims at **high transduction gain**, while rejecting the effects of parasitic forces on the mass.
- The inertial MEMS sensors require analog/mixed-signal circuitry to process and digitize the sensor output.



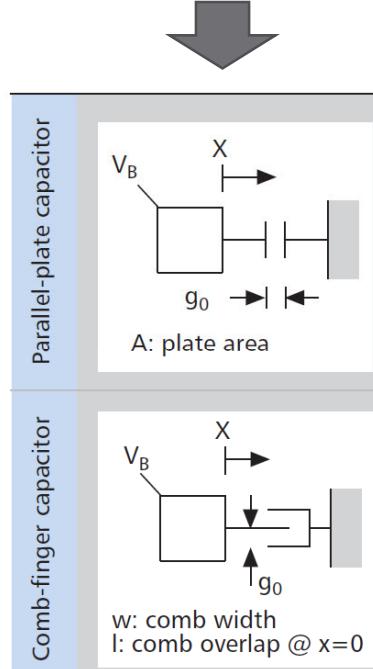
# MEMS Inertial Sensors

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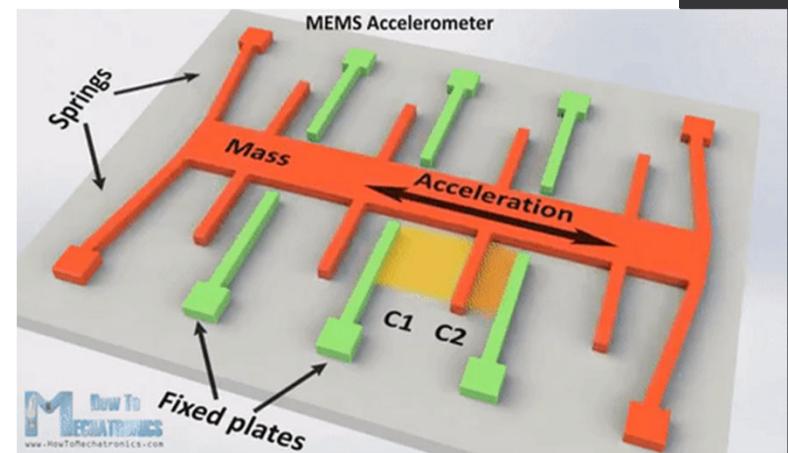
# Transduction mechanisms

## Micro-Electro-Mechanical-Systems (MEMS) technology



$$\Delta Q(\Delta x) = \frac{\partial C_S(x)}{\partial x} V_B \Delta x. \quad \Delta F(\Delta v) = \frac{\partial C_S(x)}{\partial x} V_B \Delta v.$$

Capacitance	Charge transduction	Force transduction	Spring constant
$C(x)$	$\Delta Q(\Delta x)$	$\Delta F(\Delta v)$	$k_E$
$\frac{\epsilon_0 A}{g_0 - x}$ A: plate area	$\frac{\epsilon_0 A}{g_0^2} V_B \Delta x$	$\frac{\epsilon_0 A}{g_0^2} V_B \Delta v$	$-\frac{\epsilon_0 A}{g_0^3} V_B^2$
$\frac{\epsilon_0 w(l+x)}{g_0}$ w: comb width l: comb overlap @ $x=0$	$\frac{\epsilon_0 w}{g_0} V_B \Delta x$	$\frac{\epsilon_0 w}{g_0} V_B \Delta v$	0



**Table 1.** Charge transduction, force transduction, and electrostatic spring constant for two common capacitor types.

# Basic equations

When an acceleration ( $a$ ) is applied to proof mass ( $m$ ) suspended by springs with a spring constant ( $k$ ), and having a damping ( $b$ ), then the force ( $F_{applied}$ ) acting on the proof mass is given by:

$$F_{applied} - F_{spring} - F_{damping} = m\ddot{x}$$

$$m\ddot{x} + b\dot{x} + kx = F_{applied} = ma_{applied}$$

The transfer function  $H(s)$  of the system is given by:

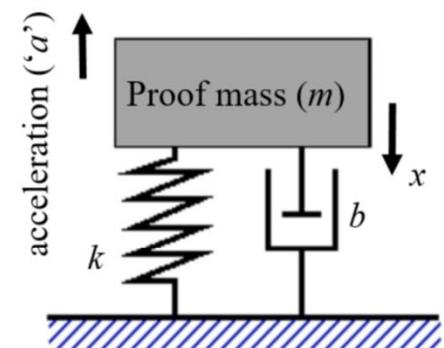
$$ms^2x(s) + bsx(s) + kx(s) = F(s) = ma(s)$$

$$s^2x(s) + \frac{b}{m}sx(s) + \frac{k}{m}x(s) = \frac{F(s)}{m} = a(s)$$

$$H(s) = \frac{x(s)}{a(s)} = \frac{1}{s^2 + \frac{b}{m}s + \frac{k}{m}} = \frac{1}{s^2 + \frac{\omega_0}{Q}s + \omega_0^2}$$

Accelerometers work in the low frequency domain ( $\omega \ll \omega_0$ ) with their mechanical sensitivity calculated by setting  $s = 0$  in the transfer function  $H(s)$  to get

$$\frac{x}{a} \sim \frac{m}{k} = \frac{1}{\omega_0^2}$$



$$\omega_0 = \sqrt{k/m}$$

$$Q = \frac{m\omega_0}{b}$$

# Sensitivity and cross-sensitivity

The sensitivity of an accelerometer is defined as the output voltage signal generated per unit input acceleration in 'g'. It is sometimes referred to as scale factor and denoted by 'S'. The general units are mV/g. For a triaxial accelerometer, the axial sensitivities are independent along the X, Y and Z axes are denoted by  $X_S$ ,  $Y_S$  and  $Z_S$ .

$$X_S = \frac{\text{Output Voltage generated (mV)}}{\text{input acceleration along X - axis (g)}}$$

$$Y_S = \frac{\text{Output Voltage generated (mV)}}{\text{input acceleration along Y - axis (g)}}$$

$$Z_S = \frac{\text{Output Voltage generated (mV)}}{\text{input acceleration along Z - axis (g)}}$$

$$(X_S)_{AY} = \frac{\text{Output Voltage generated (mV)}}{\text{input acceleration along Y - axis (g)}}$$

$$(X_S)_{AZ} = \frac{\text{Output Voltage generated (mV)}}{\text{input acceleration along Z - axis (g)}}$$

- **Dynamic range and non-linearity**

The dynamic range of the accelerometer is the maximum dynamic acceleration that can be measured accurately. It is given in ' $\pm g$ '.

$$\% \text{ Non linearity} = \frac{\text{Maximum deviation (g)}}{\text{Full scale range (g)}} \times 100$$

# Accelerometer system

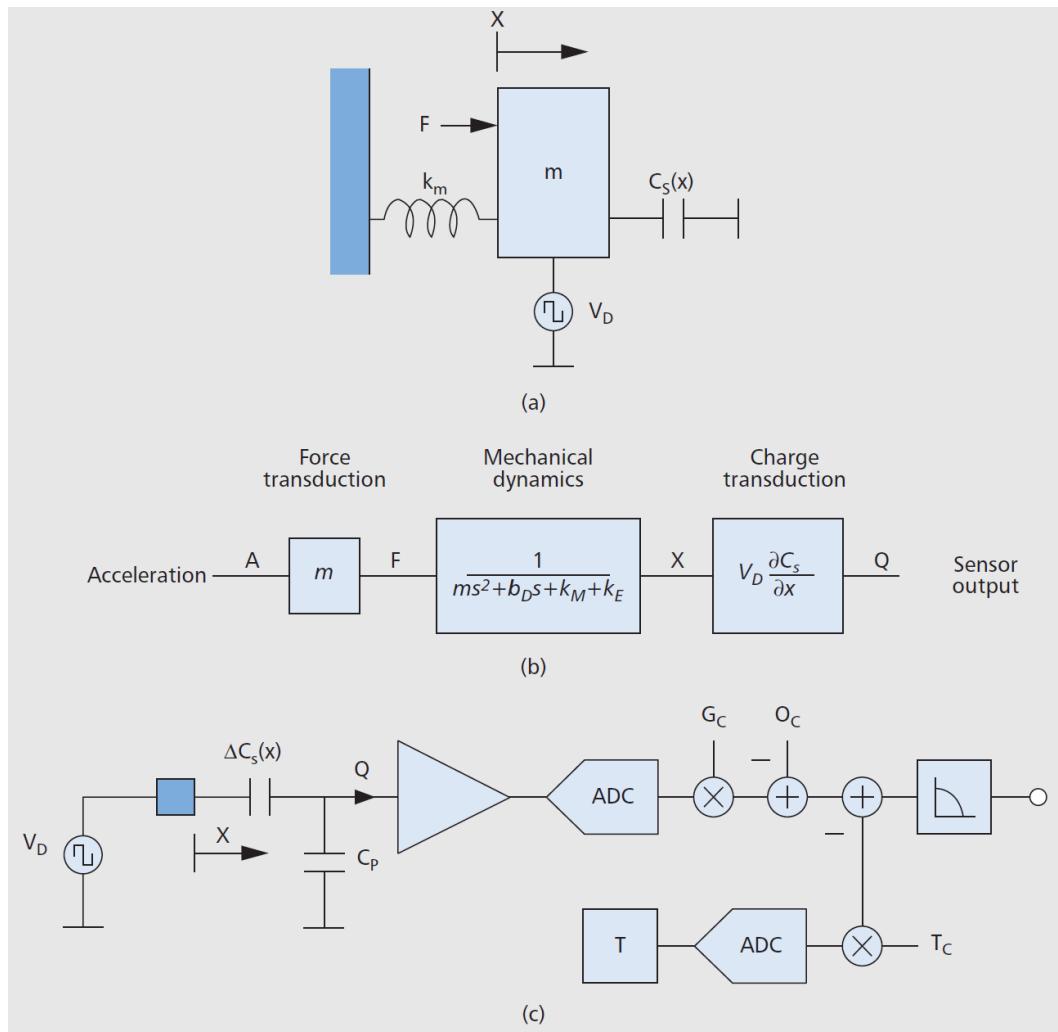


Table 1. Accelerometer Grade and Typical Application Area

Accelerometer Grade	Main Application	Bandwidth	$g$ -Range
Consumer	Motion, static acceleration	0 Hz	1 $g$
Automotive	Crash/stability	100 Hz	<200 $g/2\ g$
Industrial	Platform stability/tilt	5 Hz to 500 Hz	25 $g$
Tactical	Weapons/craft navigation	<1 kHz	8 $g$
Navigation	Submarine/craft navigation	>300 Hz	15 $g$

## Consumer applications

- Output data rates of a few kHz
- Full-scale ranges of 16g
- 12–16 bit resolution
- DC accuracy over temperature and lifetime:  
drift ~500 ppm levels (corresponding to, e.g., 10 mg for a 16g full-scale range), which implies that sub-nanometer displacements are significant for micron-scale gaps.

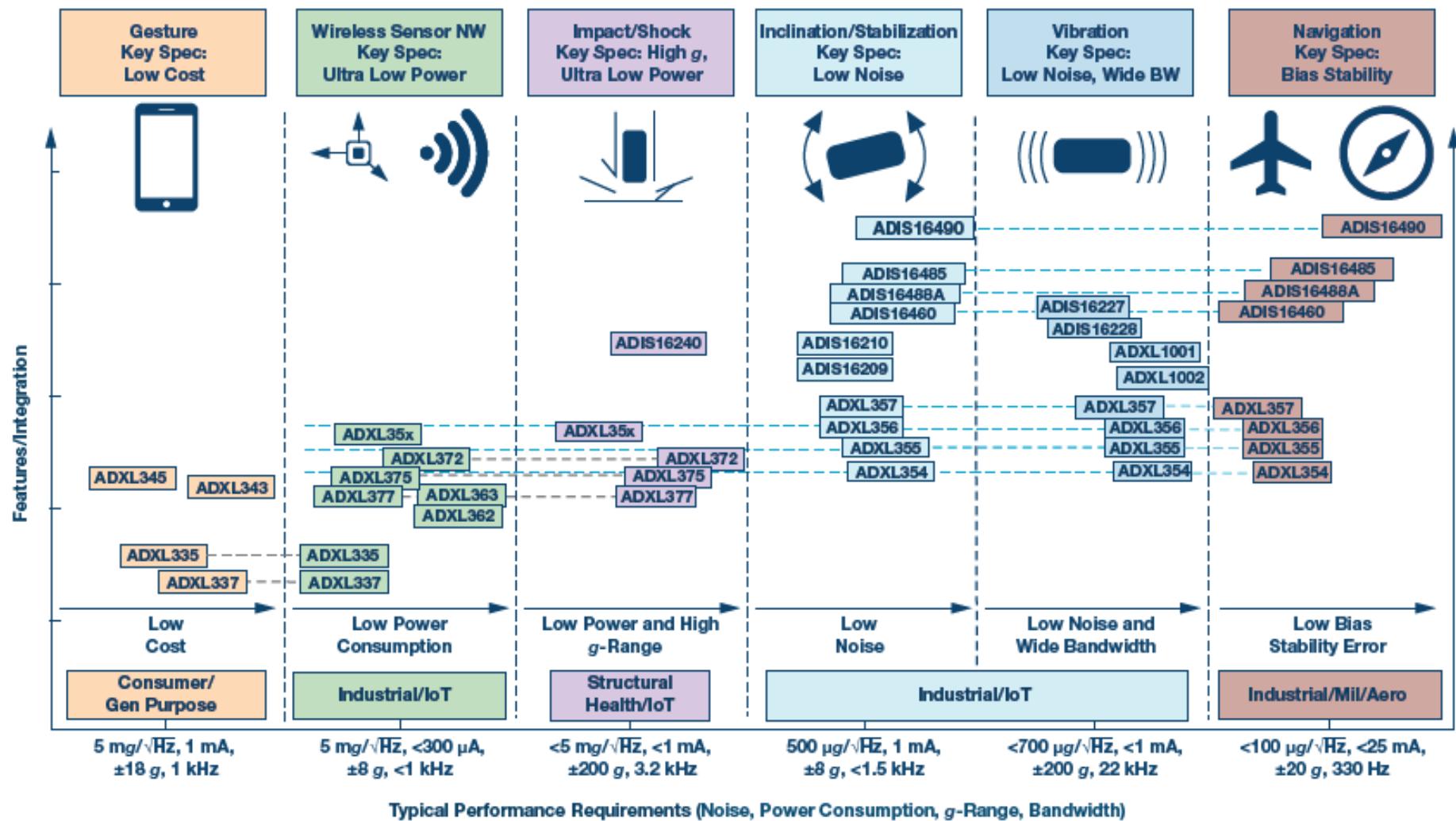


Figure 1. Application landscape for a selection of Analog Devices MEMS accelerometers.

# Case study: a capacitive MEMS accelerometer

## Two approaches to measuring acceleration

- Open loop: Measure change due to acceleration
- Closed loop: A disturbance in a position control system

## Quasi-static sensing

- ❖ Mechanical resonant frequency > Frequency of acceleration
- ❖ Measure displacement due to acceleration
- ❖ Optical, Capacitive, Piezoresistive, Tunneling

## Resonant sensing

- ❖ Measure change in resonant frequency
- ❖ Due to position-dependent nonlinear spring

Today's example involves a quasi-static accelerometer

# Basics: displacement and acceleration

**Displacement and acceleration are coupled together by a fundamental scaling law**

- A higher resonant frequency implies less displacement
- high  $f$  & low sensitivity
- Measuring small accelerations requires floppier structures
- high sensitivity and low  $f$

$$x = \frac{F}{k} = \frac{ma}{k}$$

$$x = \frac{a}{\omega_0^2}$$

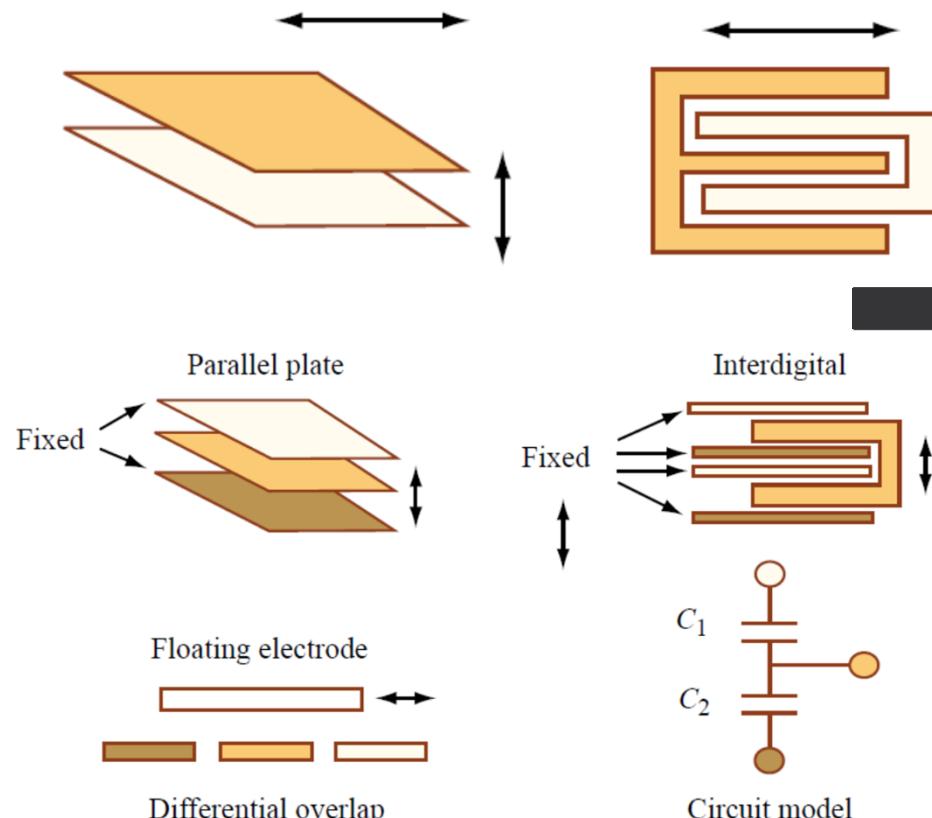
**Fundamental low Limit of detection (LoD)**

- Johnson noise in the damping mechanism

$$a_{n,rms} = \sqrt{\frac{4k_B T \omega_0}{mQ}}$$

# How to use a MEM capacitor?

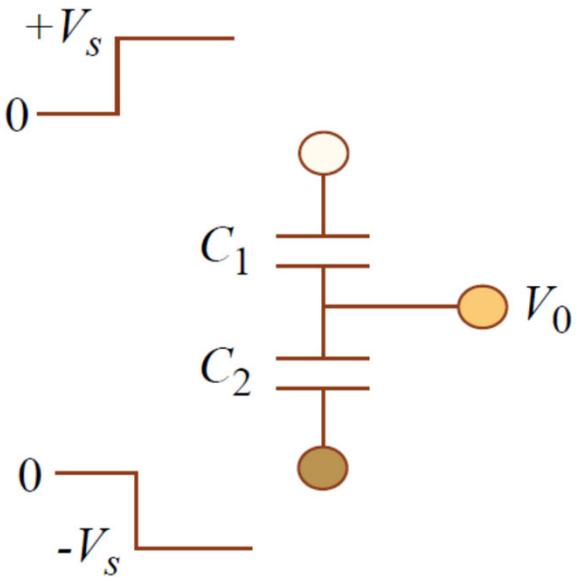
- Single MEM capacitors:
  - ❖ Capacitance is function of gap or area
  - ❖ Can be nonlinear
- Differential capacitors
  - ❖ One capacitor increases while the other decreases



Adapted from Figure 19.4 in Senturia, Stephen D. *Microsystem Design*. Boston, MA: Kluwer Academic Publishers, 2001, p. 501. ISBN: 9780792372462.

# Using a differential capacitor

- Differential drive creates sense signal proportional to capacitance difference
- Gives zero output for zero change
- Output linear with gap



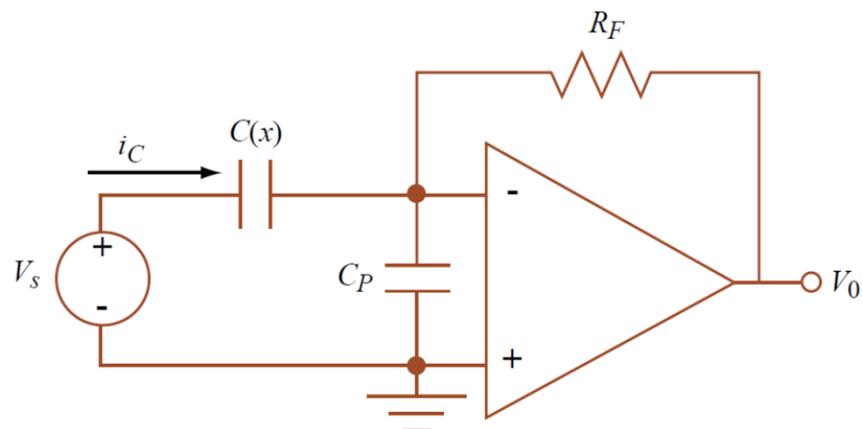
$$V_0 = -V_s + \frac{C_1}{C_1 + C_2} (2V_s) = \frac{C_1 - C_2}{C_1 + C_2} V_s$$

for parallel-plate capacitors where  
only  $g$  changes, this becomes

$$V_0 = \frac{g_2 - g_1}{g_1 + g_2} V_s$$

# Transimpedance circuit (1)

- The simplest type of circuit measures the displacement current in a capacitor using a transimpedance amplifier
- Transimpedance converts current to voltage
- Nulls out parasitic capacitance
- If source is DC, measure velocity of motion, not really what we want...



$$V_0 = -R_F V_s \frac{\partial C}{\partial x} \bigg|_{V_s} \frac{dx}{dt}$$

**constant**

# Inertial MEMS for human activity (1)

## Engineering aspects:

- Design optimization of inertial sensors aims at **high transduction gain**, while rejecting the effects of parasitic forces on the mass.
- Inertial MEMS sensors require **analog/mixed-signal circuitry** to process and digitize the sensor output.
- Important aspects for the wearability: **low power consumption and the small size**.
- The energy efficiency of inertial sensors is currently evaluated by some specific figures of merit such as a power ratio of peak SNR to energy per conversion.
- Other practical aspects (packaging, cost, etc).

# Inertial MEMS for human activity (2)

- Status in MEMS for inertial measurement:

- major technology & package progress made by ST Microelectronics, Texas Instruments and InvenSense
- ST Microelectronics (2014):
  - 3 Billions MEMS units, with manufacturing capacity larger than 3 Mu/day
  - include analog and digital accelerometer and gyroscope sensors with advanced power saving features for ultra-low-power applications.

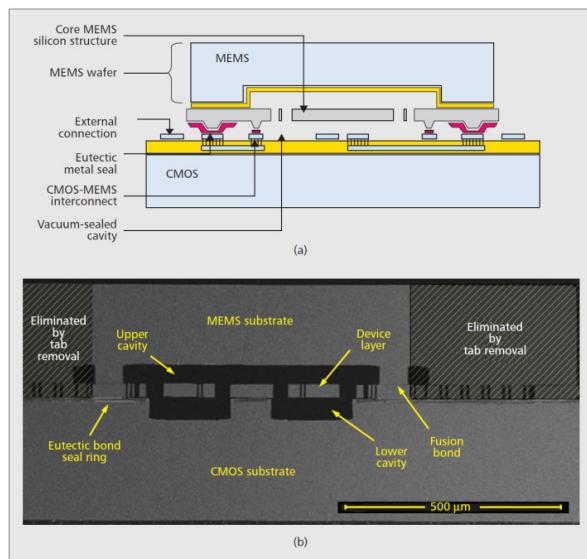
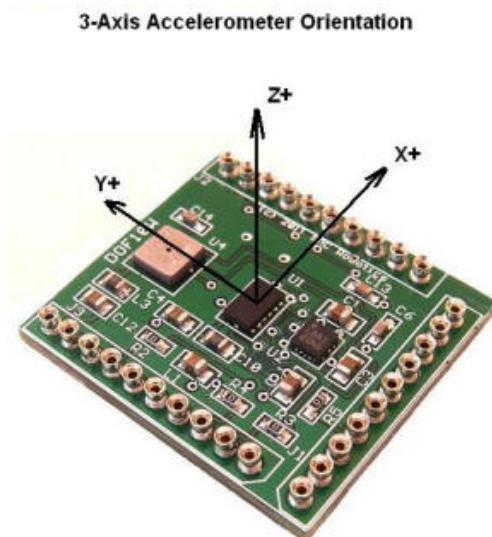
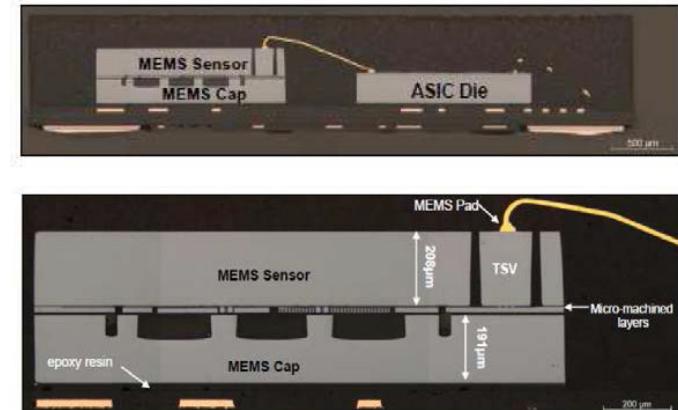


Figure 6. InvenSense silicon MEMS/CMOS fabrication technology: a) assembly; b) device cross-section.

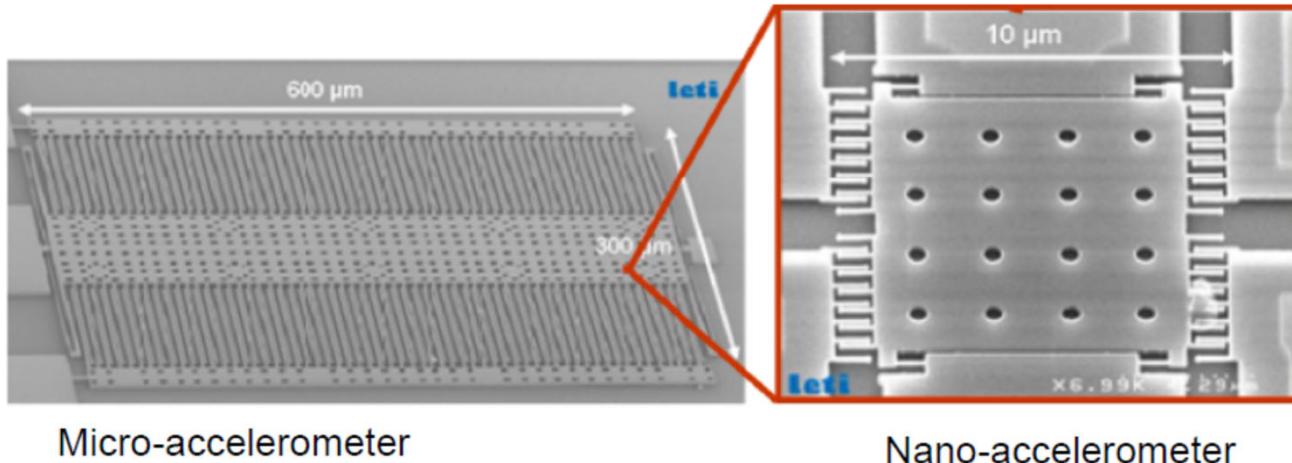
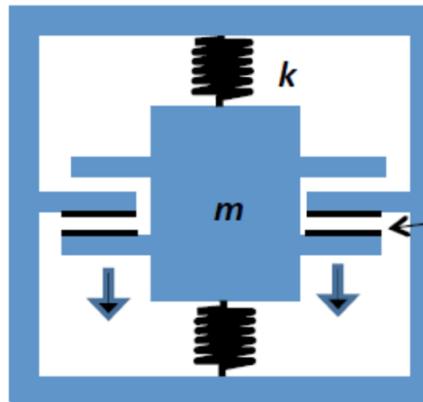


ST Microelectronics



# Ultra-low power NEMS-accelerometers

Applications : airbag (but no real need for miniaturisation), Ipod, videogames, mini-drones, etc.



SEM images of micro and nano-systems fabricated at LETI-CEA (Grenoble)

# Commercial MEMS IMU's

## Consumer MEMS success story Continuous innovation

